

Measurement of quartz crystal unit parameters —

Part 8: Test fixture for surface mounted quartz crystal units

The European Standard EN 60444-8:2003 has the status of a
British Standard

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National foreword

This British Standard is the official English language version of EN 60444-8:2003. It is identical with IEC 60444-8:2003. It supersedes PD IEC/PAS 62277:2002 which is withdrawn.

The UK participation in its preparation was entrusted to Technical Committee EPL/49, Piezo-electric devices for frequency control and selection, which has the responsibility to:

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Summary of pages

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Part 8: Test fixture for surface mounted quartz crystal units
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Mesure des paramètres
des résonateurs à quartz
Partie 8: Dispositif d'essai
pour les résonateurs à quartz
montés en surface
(CEI 60444-8:2003)

Messung von Schwingquarz-Parametern
Teil 8: Prüfaufbau für oberflächen-
montierbare Schwingquarze
(IEC 60444-8:2003)

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CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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Foreword

The text of document 49/599/FDIS, future edition 1 of IEC 60444-8, prepared by IEC TC 49, Piezoelectric and dielectric devices for frequency control and selection, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60444-8 on 2003-10-01.

The following dates were fixed:

- latest date by which the EN has to be implemented
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- latest date by which the national standards conflicting
with the EN have to be withdrawn (dow) 2006-10-01

Annexes designated "normative" are part of the body of the standard.
In this standard, annex ZA is normative.
Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 60444-8:2003 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following note has to be added for the standard indicated:

IEC 60444-4 NOTE Harmonized as EN 60444-4:1997 (not modified).

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